



## NI SEMICONDUCTOR EXCHANGE - OCTOBER 29, 2020 (AMER)

### Live Sessions Schedule

Keynote			
9:00–9:30 a.m.	The Future of Semi Test: Applying Digital Transformation Technologies to Semiconductor Product Development Ritu Favre, NI		
	Mixed Signal Track	Wireless Track	Enterprise Track
9:30–10:00 a.m.	Simplify Semiconductor Device Control Mike Watts, NI Marvin Landrum, NI	Achieve Lab-Grade RFFE Validation Results with Production Test Speed Alejandro Buritica, NI	Break Down Barriers From Design to Test George Zafiropoulos, NI
10:00–10:10 a.m.	Break		
10:10–10:40 a.m.	Optimize Semiconductor Power Efficiency Measurements Mike Watts, NI	Future of Connectivity: Wifi6 and Wifi7 Alejandro Buritica, NI	Panel: Driving Innovation with a Modern Lab Approach Moderator: Michael Schneider, NI Key panelists: Michael O'Sullivan, General Manager, Analog Devices Christian Paintz, Central Engineering Silicon Manager, Melexis Marvin Landrum, NI
10:40–11:10 a.m.	Improve WLR System Performance to Enhance Your Reliability Decisions Joris Donders, NI Karen Armendariz, Celadon Eric Wilcox, FormFactor	Address the Challenges of 5G OTA Validation from DFF to IFF Alejandro Buritica, NI	From 5G to 6G: Understanding the Next Generation of Mobile Communications Moderator: David Hall, NI Key panelists: Dr. Volker Ziegler, 6G Leadership Nokia Bell Labs & CTO Joe Madden, President of Mobile Experts Charles Schroeder, Head of Wireless Long Term Development Initiatives and Fellow at NI
11:10–11:20 a.m.	Break		
11:20–11:50 a.m.	Tips and Tricks for Better SMU Measurements Austin Stanton, NI	Accelerate 5G mmWave Beamformer Test Yuka Muto, NI Mike Mayberry, NI	Ways to Improve Operational Efficiency of Your V&V Labs Ray Hsu, NI
11:50 a.m.–12:20 p.m.	Networking	Speed Up Your Load Pull Test Vince Mallette, Focus Microwaves	Enable Machine Learning Approaches to Semiconductor Data Alon Malki, NI
12:20 – 12:50 p.m.	Networking		
Keynote			
12:30–1:00 p.m.	* The Future of Semi Test: Applying Digital Transformation Technologies to Semiconductor Product Development Ritu Favre, NI  *A repeat keynote for different timezone participants		
	Mixed Signal Track	Wireless Track	Enterprise Track
1:00–1:30 p.m.	*Simplify Semiconductor Device Control Mike Watts, NI Marvin Landrum, NI  *A repeat keynote for different timezone participants	*Achieve Lab-Grade RFFE Validation Results with Production Test Speed Alejandro Buritica, NI  *A repeat keynote for different timezone participants	*Break Down Barriers From Design to Test George Zafiropoulos, NI  *A repeat keynote for different timezone participants

[For abstract and full list of on-demand sessions, please click here.](#)

*\*Please note that this agenda is still subject to change.*